

## V23809-E1-E30 8B/10B V23809-E1-E40 1300 nm ESCON® Parallel Transceiver Preliminary Data Sheet

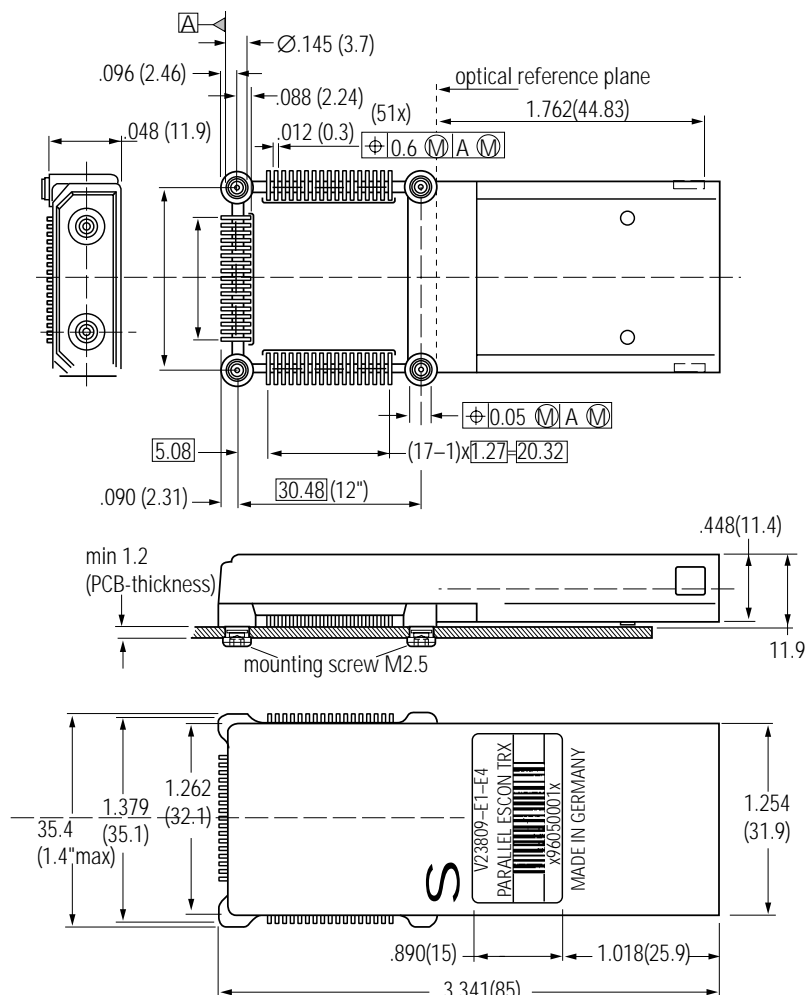
### FEATURES

- Complies with ESCON and SBCON standards
- Fully compatible with parallel transceiver V23806-A6-X1
- Transceiver includes clock recovery module, P-S /S-P and ESCON/SBCON receptacle
- Optional 8B/10B coder/decoder function (E40 only)
- SMT component for easy mounting on surface mount PC boards
- Transceiver mates keyed ESCON/ SBCON connector
- Data rates for ESCON/SBCON applications from 100 to 200 MBaud
- Data rates for individual applications from 100 to 300 MBaud
- Transmission distance of 3 km and more
- Single power supply of 3.0 V to 5.5 V (E40 only)
- Extremely low power consumption <2 W at 3.3 V (E40 only)
- All inputs and outputs TTL compatible
- Excellent EMI performance
- System optimized for 62.5 and 50  $\mu$ m graded index fiber
- 0.7" spacing between optical interface of transmitter and receiver
- Low profile for high slot density

### APPLICATIONS

- ESCON architecture
- High speed computer links
- Local area networks
- High definition/digital television
- Switching systems
- Control systems
- FC transceiver version with SC duplex shell planned

Dimensions in inches (mm)



### Maximum Ratings (Absolute maximum stress)

Exceeding any one of these values may destroy the device immediately. However, the electro-optical characteristics described in the following tables are only valid for use under the recommended operating conditions.

Power Dissipation (PD)	2 W
Supply voltage ( $V_{CC}-V_{EE}$ )	-0.5 V to 7 V
Maximum Input Voltage ( $V_{IN}$ )	$V_{EE}$ to $V_{CC}$
Operating Case Temperature ( $T_{case}$ )	-25 to 85°C
Humidity/Temperature Test Condition ( $R_H$ )	85/85 %°C
Lifetime Condition ( $T_{amb}/life$ )	115/1000°C/h
Soldering Conditions Temp/Time ( $T_{solder}$ )	260/10°C/s
ESD Resistance (all pins to $V_{EE}$ , Human Body) (ESD)	1.5 kV
Output Current ( $I_O$ )	50 mA

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Transmitter	Sym.	Min.	Typ.	Max.	Units
Center Wavelength <sup>(5, 6)</sup>	I <sub>C</sub>	1285		1355	nm
Spectral Width (FWHM) <sup>(6)</sup>	σλ			160	
Temperature Coefficient, Optical Output Power	TCp			0.03	dB/°C
Output Rise/Fall Time, 20–80% <sup>(6)</sup>	t <sub>R</sub> , t <sub>F</sub>		1	1.7 (2)	ns
Deterministic Jitter <sup>(8)</sup>	J <sub>d</sub>		0.6	0.8	
Random Jitter <sup>(9)</sup>	J <sub>r</sub>			0.06	
Extinction Ratio (dynamic) <sup>(10)</sup>	ER		–16	–13	dB

#### Notes

- Transmitter operating at 200 MBaud and 50% duty cycle.
- Measured at the end of 1 meter fiber, cladding modes removed at a data rate of between 50 and 200 MBaud, 50% duty cycle.
- Po [dBm]=10 log (Po/1 mW)
- Po (BOL) >–20dBm and Po (EOL) >–21.5 dBm at T<sub>case</sub>=60°C.
- Measured at T<sub>case</sub>=60°C
- Full width, half magnitude of peak wavelength: special relationship between λ<sub>c</sub>, dλ, tr/tf according to FC-PH Rev 4.3 Paragraph 6.3.2. and Fig.26. Spectral width must be considered.
- Over 10<sup>5</sup> hours lifetime at T<sub>amb</sub>=35°C
- Deterministic Jitter, measured at 200 MBaud with Jitter Test Pattern shown in Figure 5. In the Test Pattern are five positive and five negative transitions. Measure the time of the 50% crossing of all 10 transitions. The time of each crossing is then compared to the mean expected time of the crossing. The DJ is the range of the timing variations.
- RMS value measured with 1010 pattern at 200 Mbaud. Peak-to-peak value is determined as RMS multiplied by 14 for BER 1E-12.
- Extinction ratio is the logarithmic measure of the optical power in the OFF state (POFF) to twice the average power (P0):  
ER=10 log [(2xP0)/POFF]; optical power measured in mW or  
ER=ΩP0+3dBΩ–POFF; optical power measured in dBm

#### Receiver Electro-Optical Characteristics

(Values in parentheses are for 300 MBd)

Receiver	Sym.	Min.	Typ.	Max.	Units
Data Rate	Dr	100		200 (300)	MBaud
Supply Current <sup>(1)</sup>	I <sub>CC</sub>			100	mA
Sensitivity (Average Power) BOL <sup>(2, 3, 4)</sup>	P <sub>IN</sub>	–32.5 (–29)	–35.5		dBm
Sensitivity (Average Power) EOL <sup>(2, 3, 4, 5)</sup>		–32 (–28.5)	–35		
Saturation (Average Power)	P <sub>SAT</sub>	–14			
Signal Detect Assert Level <sup>(6)</sup>	P <sub>SDA</sub>	–44.5		–36,0	
Signal Detect Deassert Level <sup>(6)</sup>	P <sub>SDD</sub>	–45		–37.5	
Signal Detect Hysteresis	P <sub>SDA</sub> – P <sub>SDD</sub>	0.5	1.5	3	dB
Signal Detect Reaction Time	SDreac	3		500	μs

Receiver	Sym.	Min.	Typ.	Max.	Units
Signal Detect Hysteresis	P <sub>SDA</sub> – P <sub>SDD</sub>	0.5	1.5	3	dB
Signal Detect Reaction Time	SDreac	3		500	μs
Max. Deterministic Jitter Optical Input <sup>(7, 9)</sup>	J <sub>d</sub>			0.19	% of Unit Intervals
Max. Random Jitter RMS Optical Input <sup>(8, 9)</sup>	J <sub>r</sub>			0.09	

#### Notes

- For V<sub>CC</sub>–V<sub>EE</sub> (min, max). 50% duty cycle.
- Measured at the end of 1 meter fiber, cladding modes removed at a data rate of between 50 and 200 MBaud, 50% duty cycle.
- Po [dBm]=10 log (Po [mW])
- Measured at BER=1E-12, 200 MBaud transmission rate and 50% duty cycle 2<sup>7</sup>–1 PRBS pattern; center wavelength between 1200nm and 1500 nm, fiber type 62.5/125 μm/0.29 NA or 50/125 μm/0.2 NA; input optical rise and fall times are 1.2 ns and 1.5 ns (20% - 80%) respectively.
- Over 10<sup>5</sup> hours lifetime at T<sub>amb</sub>=35°C
- Indicates the presence or absence of optical power at the receiver input. Signal detect at logic "high" when asserted. All powers are average power levels. Pattern 2<sup>7</sup>–1 at 200 MBaud.
- Deterministic Jitter measured at 200 MBaud with Jitter Test Pattern shown in Figure 5. In the test pattern are five positive and five negative transitions. Measure the time of the 50% crossing of all 10 transitions. The time of each crossing is then compared to the mean expected time of the crossing. The DJ is the range of the timing variations.
- To convert from specified RMS value to peak-to-peak value (at BER 1E-12) multiply value by 14.
- Jitter at optical input. Jitter magnitudes above specified level may increase the bit error rate.

#### Transceiver Pin Description 10 Bit Interface: FSOL Mode

In this mode the transceiver is compatible with the former version, V23806-A6-X1

Pin#	Pin Name	Level/Logic	Description
1, 6, 9, 26, 43, 45, 48, 51	Vee	Power Supply	Ground attached to the case
2	Vcc PRE		Preamplifier positive power supply
3	SIGDET	TTL out	Signal detected
4	LOCKREF	TTL in	Control input for RX PLL
5	SYNCEN		Control of byte alignment operation
7,8	VccFAST	Power Supply	Bipolar IC positive power supply
10 to 19	Dout a to j	TTL out	Data output parallel 10 channels
20	RBCLK	TTL out	Read byte clock
21	PAROUT		Parity bit out
22	BSYNC		Byte synchronization operation
23	PARERR	TTL out	Parity bit error

Pin#	Pin Name	Level/Logic	Description
24,25	VccSLOW	Power Supply	Logic positive power supply
27	Loopsel a	TTL in	Test loop select
28	Loopsel b		
29	RESREC		Receiver reset
30	RESFF		Reset all flip-flops
31	TBCLK		Transmit byte clock
32	PARIN		Parity bit in
33 to 42	Din j to a		Data input parallel 10 channels
44	TESTCLK		Test clock. In test mode this clock is the bit clock
46	TESTMOD		If this signal is low TESTCLK is used
47	TXOFF		Transceiver off when logical high
49,50	Vcc DRI	Power Supply	LED driver positive power supply

#### Transceiver Pin Description 8 Bit interface: PSOL Mode (E40 only)

Pin#	Pin Name	Level/Logic	Description
1, 6, 26, 43, 45, 48, 51	Vee	Power Supply	Ground attached to the case
2	Vcc PRE		Preamplifier positive power supply
3	SIGDET	TTL out	Signal detected
4	$\overline{R}$		Read pulse for external FIFOs
5	SYNCEN	TTL in	Control of byte alignment operation
7,8	VccFAST	Power Supply	Positive power supply of the bipolar IC
9	$\overline{PSOL1/PSOL2}$	TTL in	Mode select for PSOL Mode 1 or Mode 2
10	RK	TTL out	Receiver special character flag
11 to 18	Dout A to H		Decoded data output parallel 8 channels
19	RCV		Receiver code violation
20	RBCLK		Read byte clock
21	PAROUT		Parity bit out
22	$\overline{W}$		Write pulse for external FIFOs
23	PARERR		Parity bit error
24, 25	VccSLOW	Power Supply	Logic positive power supply

Pin#	Pin Name	Level/Logic	Description
27	Loopsel a	TTL in	Test loop select
28	Loopsel b		
29	$\overline{EPI}$		Enable parallel input
30	$\overline{ENPI}$		Enable next parallel input
31	TBCLK		Transmit byte clock
32	PARIN		Parity bit in
33	TCV		Transmitter code violation
34 to 41	Din H to A		Uncoded data input parallel 8 channels
42	TK		Transmitter special character flag
44	$\overline{RAW/COD}$		Select Raw Mode/Coder Mode
46	$\overline{BIST}$		Enable built-in self test
47	TXOFF		Transceiver off when logical high
49, 50	Vcc DRI	Power Supply	LED driver positive power supply

Figure 4. Signal detect threshold and hysteresis

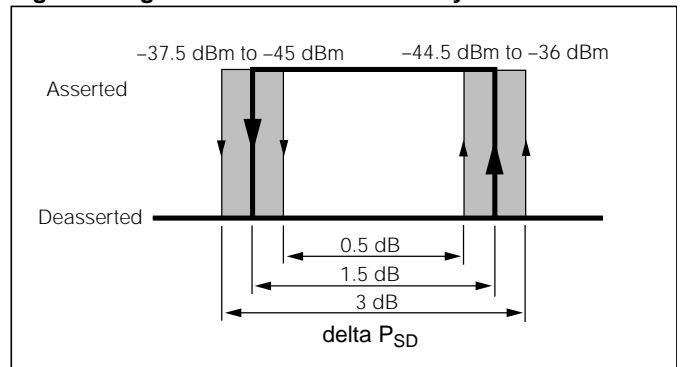
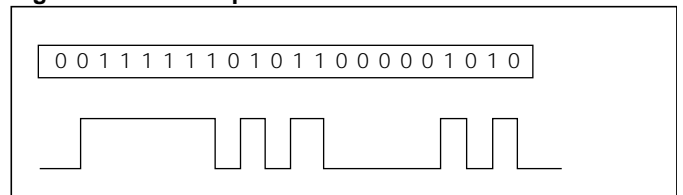


Figure 5. Jitter test pattern



## Power Supply Filtering

The Siemens ESCON Transceiver Family provides superior EMI performance regarding emission and immission of radiation and provides immunity against conductive noise. Some basic recommendations are given in this document to ensure proper functionality in the field.

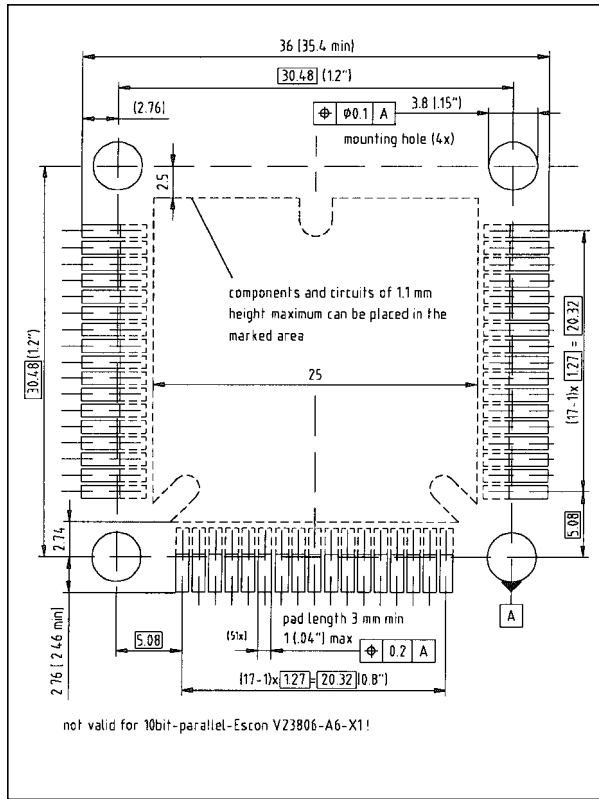
The observance of normal design rules for high speed digital systems is sufficient to ensure safe operation.

The diagram illustrates a VCC Plane layout. A central vertical bar is labeled "Slots" at the top. To the left of this bar is a vertical strip of horizontal lines labeled "VccCMOS". To the right, a horizontal strip of horizontal lines is labeled "VccBIP". Below the "VccBIP" strip, a horizontal line is labeled "VccPRE". Further down, another horizontal strip of horizontal lines is labeled "VccDRI". The entire layout is enclosed within a jagged, irregular boundary. The text "VCC Plane" is located at the bottom center of the diagram.

5

**Figure 7. Recommended footprint**

The avoidance of any component or non-isolated structure, like tracks or vias, under the transceiver is strongly recommended.



**Figure 8. Power-on sequence in FSOL mode**

